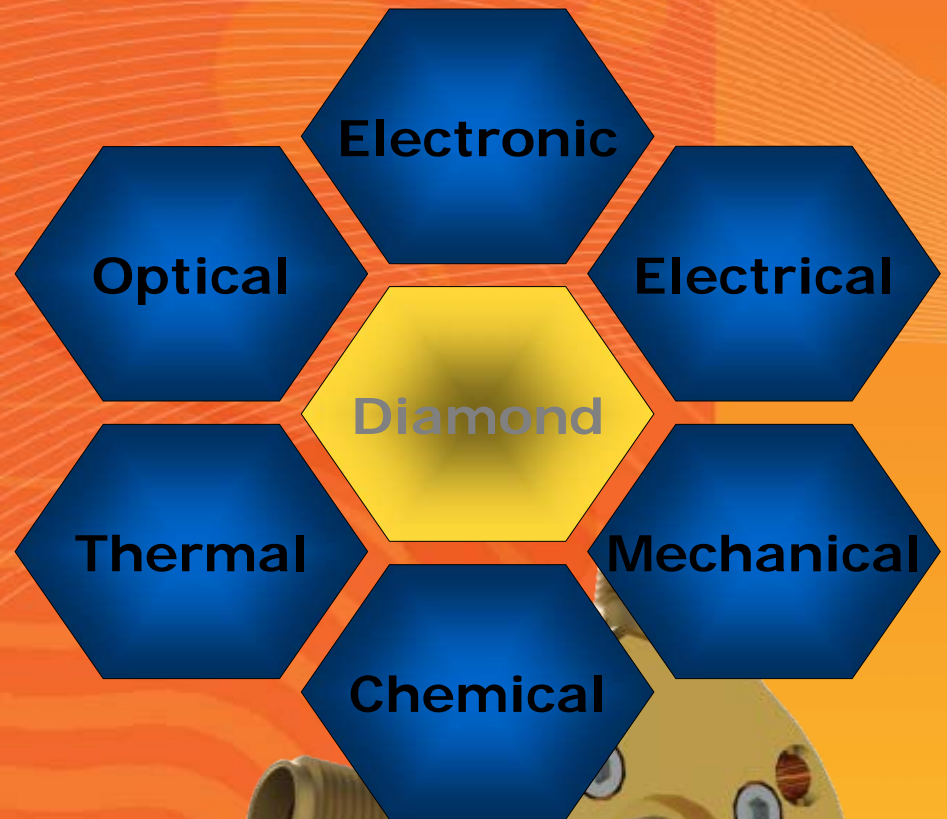


- Broad transmission spectrum
- Highest thermal conductivity
- Highest resistance to thermal shock
- Low thermal expansion coefficient
- High chemical (bio) inertness
- Highest Young's modulus
- Highest Knoop hardness
- High tensile strength
- Good electrical insulator
- Good electrical conductor (doped)
- Low dielectric constant
- Low dielectric loss
- Wide electronic band gap
- High electronic mobility



Diamond radiation detectors are able to detect deep UV photons, X-rays, gamma rays, electrons, alpha particles, charged ions and neutrons, with a dynamic range in energies spanning from 5.5 eV up to GeV of cosmic rays.

Since the bandgap of diamond is 5.5 eV this leads into a negligible dark current noise at room temperature with no need for cooling.

Metal diamond interfaces play a key role in the performance of the detectors as different metallization techniques lead to either “ohmic” or Schottky electrical contacts.

Intrinsic Properties

Radiation Hardness

Wide band gap 5.5eV (no thermally generated noise)

Low Z (tissue equivalent)

Low energy absorption

High thermal conductivity

High Hole and Electron Mobility

Detector Properties

High sensitivity

Good spatial and temporal resolution achievable

Low leakage currents and stable
($< 0.01\text{pA} / \text{pixel}$)

Low capacitance

Device Advantages

Intrinsically simple device (no pn junction required)

can fabricate robust, compact devices

High temperature operation (no need for cooling)

Applications Include:

High Energy Physics

Civil Nuclear

Medical Therapy / Dosimetry (X-ray & Particle Therapies)

Synchrotrons and Cyclotrons

Radiation Monitoring (nuclear, medical and oil & gas)

Deep UV ($< 240\text{nm}$)

Intrinsic Material Properties

	Si	4H-SiC	GaN	Natural Diamond	CVD Diamond	Potential device application benefit
Bandgap (eV)	1.1	3.2	3.44	5.47	5.47	High temperature
Breakdown field (MVcm ⁻¹)	0.3	3	5	10	10	High voltage
Electron saturation velocity (x10 ⁷ cm s ⁻¹)	0.86	3	2.5	2	2	High frequency
Hole saturation velocity (x10 ⁷ cm s ⁻¹)	n/a	n/a	n/a	0.8	0.8	
Electron mobility (cm ² V ⁻¹ s ⁻¹)	1450	900	440	200–2800	4500	
Hole mobility (cm ² V ⁻¹ s ⁻¹)	480	120	200	1800–2100	3800	
Thermal conductivity (Wcm ⁻¹ K ⁻¹)	1.5	5	1.3	22	24	High power
Johnson's figure of merit	1	410	280	8200	8200	Power-frequency product
Keyes' figure of merit	1	5.1	1.8	32	32	Transistor behavior thermal limit
Baliga's figure of merit	1	290	910	882	17200	Unipolar HF device performance

Isberg J., *et al.*, *Science* (2002) 297, 1670

Chris J. H. Wort* and Richard S. Balmer

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